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## Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

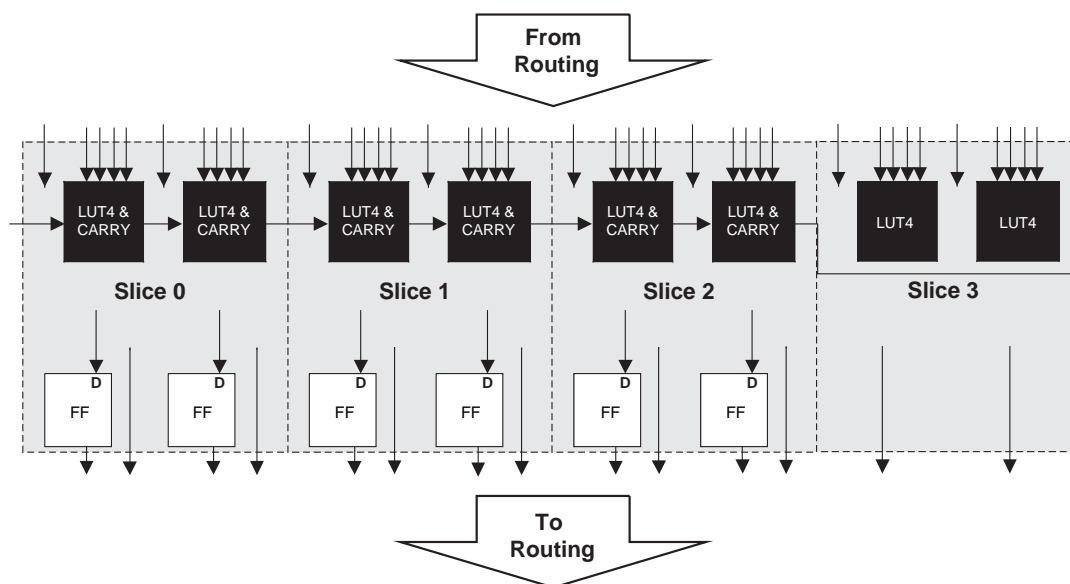
## Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

### Details

Product Status	Active
Number of LABs/CLBs	625
Number of Logic Elements/Cells	5000
Total RAM Bits	169984
Number of I/O	146
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/lattice-semiconductor/lfxp2-5e-7qn208c">https://www.e-xfl.com/product-detail/lattice-semiconductor/lfxp2-5e-7qn208c</a>

**Figure 2-2. PFU Diagram**



## Slice

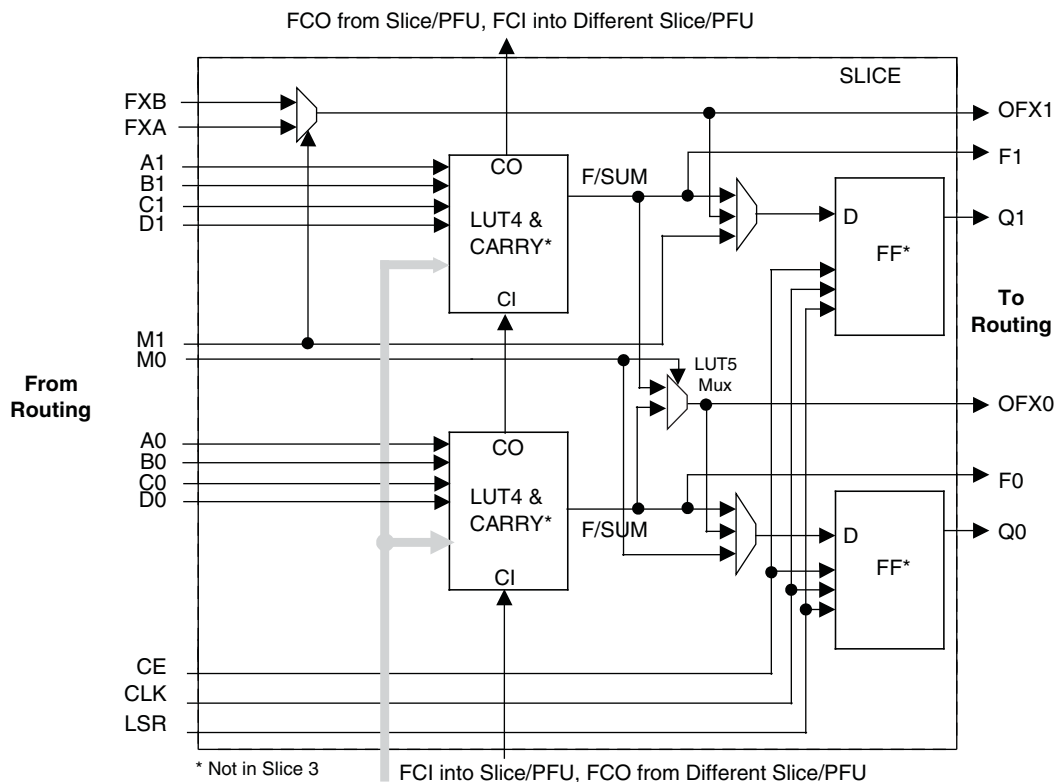
Slice 0 through Slice 2 contain two 4-input combinatorial Look-Up Tables (LUT4), which feed two registers. Slice 3 contains two LUT4s and no registers. For PFUs, Slice 0 and Slice 2 can also be configured as distributed memory, a capability not available in PFF blocks. Table 2-1 shows the capability of the slices in both PFF and PFU blocks along with the operation modes they enable. In addition, each PFU contains logic that allows the LUTs to be combined to perform functions such as LUT5, LUT6, LUT7 and LUT8. There is control logic to perform set/reset functions (programmable as synchronous/asynchronous), clock select, chip-select and wider RAM/ROM functions. Figure 2-3 shows an overview of the internal logic of the slice. The registers in the slice can be configured as positive/negative edge triggered or level sensitive clocks.

**Table 2-1. Resources and Modes Available per Slice**

Slice	PFU BBlock		PFF Block	
	Resources	Modes	Resources	Modes
Slice 0	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM	2 LUT4s and 2 Registers	Logic, Ripple, ROM
Slice 1	2 LUT4s and 2 Registers	Logic, Ripple, ROM	2 LUT4s and 2 Registers	Logic, Ripple, ROM
Slice 2	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM	2 LUT4s and 2 Registers	Logic, Ripple, ROM
Slice 3	2 LUT4s	Logic, ROM	2 LUT4s	Logic, ROM

Slice 0 through Slice 2 have 14 input signals: 13 signals from routing and one from the carry-chain (from the adjacent slice or PFU). There are seven outputs: six to routing and one to carry-chain (to the adjacent PFU). Slice 3 has 13 input signals from routing and four signals to routing. Table 2-2 lists the signals associated with Slice 0 to Slice 2.

**Figure 2-3. Slice Diagram**



For Slices 0 and 2, memory control signals are generated from Slice 1 as follows:

WCK is CLK  
WRE is from LSR  
DI[3:2] for Slice 2 and DI[1:0] for Slice 0 data  
WAD [A:D] is a 4bit address from slice 1 LUT input

**Table 2-2. Slice Signal Descriptions**

Function	Type	Signal Names	Description
Input	Data signal	A0, B0, C0, D0	Inputs to LUT4
Input	Data signal	A1, B1, C1, D1	Inputs to LUT4
Input	Multi-purpose	M0	Multipurpose Input
Input	Multi-purpose	M1	Multipurpose Input
Input	Control signal	CE	Clock Enable
Input	Control signal	LSR	Local Set/Reset
Input	Control signal	CLK	System Clock
Input	Inter-PFU signal	FCI	Fast Carry-In <sup>1</sup>
Input	Inter-slice signal	FXA	Intermediate signal to generate LUT6 and LUT7
Input	Inter-slice signal	FXB	Intermediate signal to generate LUT6 and LUT7
Output	Data signals	F0, F1	LUT4 output register bypass signals
Output	Data signals	Q0, Q1	Register outputs
Output	Data signals	OFX0	Output of a LUT5 MUX
Output	Data signals	OFX1	Output of a LUT6, LUT7, LUT8 <sup>2</sup> MUX depending on the slice
Output	Inter-PFU signal	FCO	Slice 2 of each PFU is the fast carry chain output <sup>1</sup>

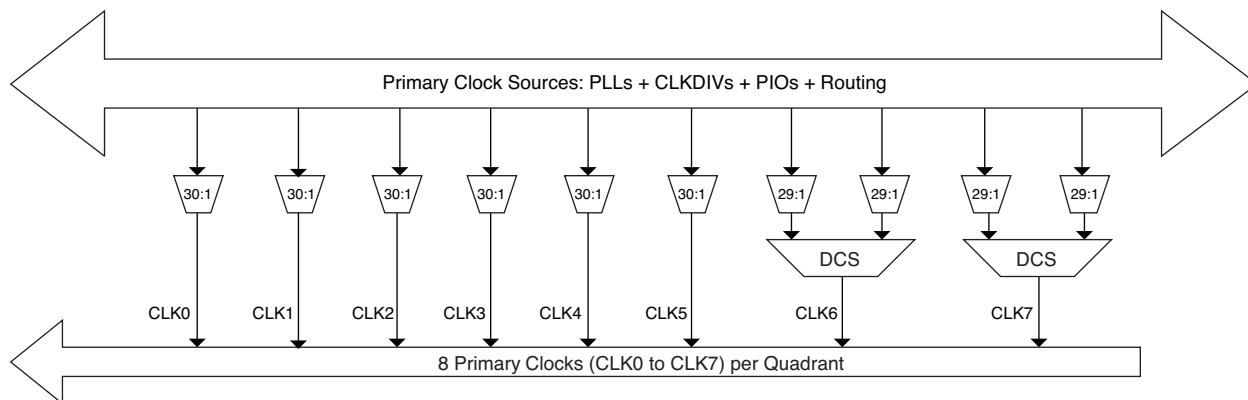
1. See Figure 2-3 for connection details.

2. Requires two PFUs.

## Primary Clock Routing

The clock routing structure in LatticeXP2 devices consists of a network of eight primary clock lines (CLK0 through CLK7) per quadrant. The primary clocks of each quadrant are generated from muxes located in the center of the device. All the clock sources are connected to these muxes. Figure 2-9 shows the clock routing for one quadrant. Each quadrant mux is identical. If desired, any clock can be routed globally.

**Figure 2-9. Per Quadrant Primary Clock Selection**

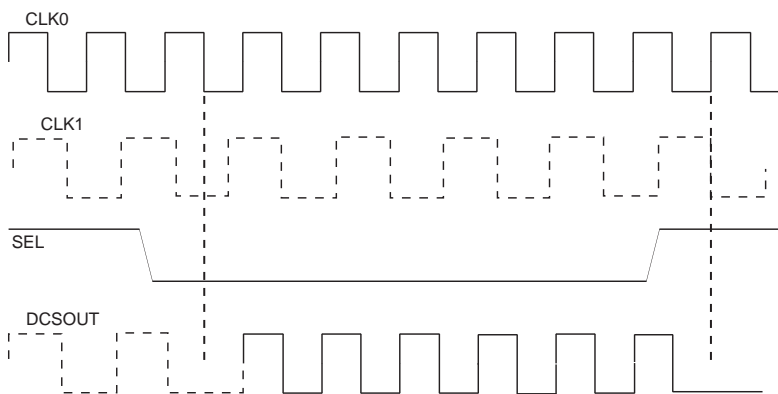


## Dynamic Clock Select (DCS)

The DCS is a smart multiplexer function available in the primary clock routing. It switches between two independent input clock sources without any glitches or runt pulses. This is achieved irrespective of when the select signal is toggled. There are two DCS blocks per quadrant; in total, eight DCS blocks per device. The inputs to the DCS block come from the center muxes. The output of the DCS is connected to primary clocks CLK6 and CLK7 (see Figure 2-9).

Figure 2-10 shows the timing waveforms of the default DCS operating mode. The DCS block can be programmed to other modes. For more information on the DCS, please see TN1126, [LatticeXP2 sysCLOCK PLL Design and Usage Guide](#).

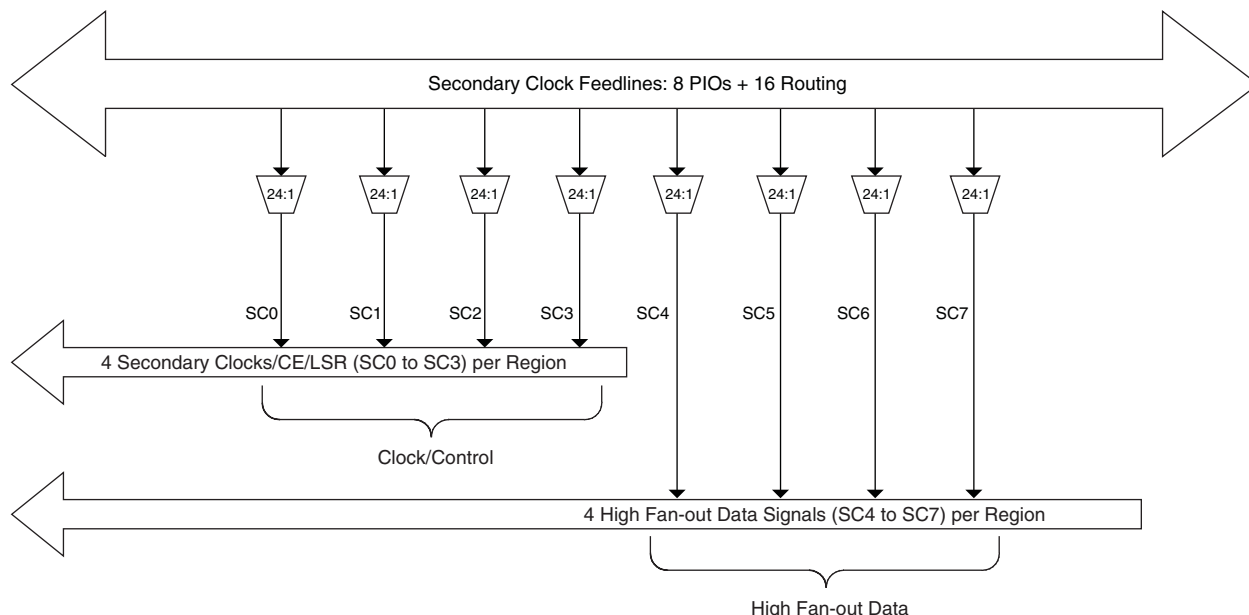
**Figure 2-10. DCS Waveforms**



## Secondary Clock/Control Routing

Secondary clocks in the LatticeXP2 devices are region-based resources. The benefit of region-based resources is the relatively low injection delay and skew within the region, as compared to primary clocks. EBR rows, DSP rows and a special vertical routing channel bound the secondary clock regions. This special vertical routing channel aligns with either the left edge of the center DSP block in the DSP row or the center of the DSP row. Figure 2-11 shows this special vertical routing channel and the eight secondary clock regions for the LatticeXP2-40.

**Figure 2-12. Secondary Clock Selection**

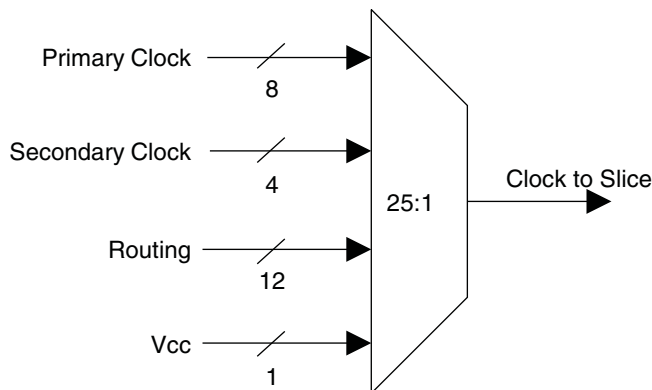


## Slice Clock Selection

Figure 2-13 shows the clock selections and Figure 2-14 shows the control selections for Slice0 through Slice2. All the primary clocks and the four secondary clocks are routed to this clock selection mux. Other signals, via routing, can be used as clock inputs to the slices. Slice controls are generated from the secondary clocks or other signals connected via routing.

If none of the signals are selected for both clock and control, then the default value of the mux output is 1. Slice 3 does not have any registers; therefore it does not have the clock or control muxes.

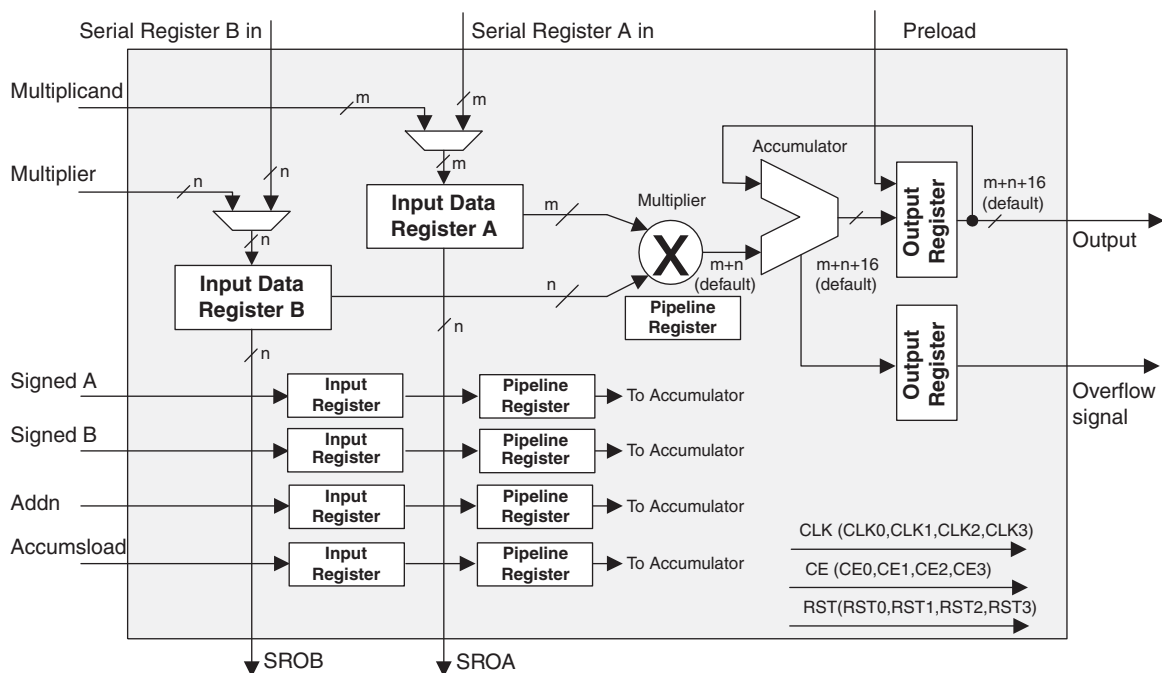
**Figure 2-13. Slice0 through Slice2 Clock Selection**



## MAC sysDSP Element

In this case, the two operands, A and B, are multiplied and the result is added with the previous accumulated value. This accumulated value is available at the output. The user can enable the input and pipeline registers but the output register is always enabled. The output register is used to store the accumulated value. The Accumulators in the DSP blocks in LatticeXP2 family can be initialized dynamically. A registered overflow signal is also available. The overflow conditions are provided later in this document. Figure 2-21 shows the MAC sysDSP element.

**Figure 2-21. MAC sysDSP**



## Tristate Register Block

The tristate register block provides the ability to register tri-state control signals from the core of the device before they are passed to the sysIO buffers. The block contains a register for SDR operation and an additional latch for DDR operation. Figure 2-27 shows the Tristate Register Block with the Output Block

In SDR mode, ONEG1 feeds one of the flip-flops that then feeds the output. The flip-flop can be configured as D-type or latch. In DDR mode, ONEG1 and OPOS1 are fed into registers on the positive edge of the clock. Then in the next clock the registered OPOS1 is latched. A multiplexer running off the same clock cycle selects the correct register for feeding to the output (D0).

## Control Logic Block

The control logic block allows the selection and modification of control signals for use in the PIO block. A clock signal is selected from general purpose routing, ECLK1, ECLK2 or a DQS signal (from the programmable DQS pin) and is provided to the input register block. The clock can optionally be inverted.

## DDR Memory Support

PICs have additional circuitry to allow implementation of high speed source synchronous and DDR memory interfaces.

PICs have registered elements that support DDR memory interfaces. Interfaces on the left and right edges are designed for DDR memories that support 16 bits of data, whereas interfaces on the top and bottom are designed for memories that support 18 bits of data. One of every 16 PIOs on the left and right and one of every 18 PIOs on the top and bottom contain delay elements to facilitate the generation of DQS signals. The DQS signals feed the DQS buses which span the set of 16 or 18 PIOs. Figure 2-28 and Figure 2-29 show the DQS pin assignments in each set of PIOs.

The exact DQS pins are shown in a dual function in the Logic Signal Connections table in this data sheet. Additional detail is provided in the Signal Descriptions table. The DQS signal from the bus is used to strobe the DDR data from the memory into input register blocks. For additional information on using DDR memory support please see TN1138, [LatticeXP2 High Speed I/O Interface](#).

## Density Shifting

The LatticeXP2 family is designed to ensure that different density devices in the same family and in the same package have the same pinout. Furthermore, the architecture ensures a high success rate when performing design migration from lower density devices to higher density devices. In many cases, it is also possible to shift a lower utilization design targeted for a high-density device to a lower density device. However, the exact details of the final resource utilization will impact the likely success in each case.



## Initialization Supply Current<sup>1, 2, 3, 4, 5</sup>

Over Recommended Operating Conditions

Symbol	Parameter	Device	Typical (25°C, Max. Supply) <sup>6</sup>	Units
$I_{CC}$	Core Power Supply Current	XP2-5	20	mA
		XP2-8	21	mA
		XP2-17	44	mA
		XP2-30	58	mA
		XP2-40	62	mA
$I_{CCAUX}$	Auxiliary Power Supply Current <sup>7</sup>	XP2-5	67	mA
		XP2-8	74	mA
		XP2-17	112	mA
		XP2-30	124	mA
		XP2-40	130	mA
$I_{CCPLL}$	PLL Power Supply Current (per PLL)		1.8	mA
$I_{CCIO}$	Bank Power Supply Current (per Bank)		6.4	mA
$I_{CCJ}$	VCCJ Power Supply Current		1.2	mA

1. For further information on supply current, please see TN1139, [Power Estimation and Management for LatticeXP2 Devices](#).

2. Assumes all outputs are tristated, all inputs are configured as LVCMOS and held at the  $V_{CCIO}$  or GND.

3. Frequency 0 MHz.

4. Does not include additional current from bypass or decoupling capacitor across the supply.

5. A specific configuration pattern is used that scales with the size of the device; consists of 75% PFU utilization, 50% EBR, and 25% I/O configuration.

6.  $T_J = 25^\circ\text{C}$ , power supplies at nominal voltage.

7. In fpBGA and ftBGA packages the PLLs are connected to and powered from the auxiliary power supply. For these packages, the actual auxiliary supply current is the sum of  $I_{CCAUX}$  and  $I_{CCPLL}$ . For csBGA, PQFP and TQFP packages the PLLs are powered independent of the auxiliary power supply.

## sysIO Recommended Operating Conditions

### Over Recommended Operating Conditions

Standard	V <sub>CCIO</sub>			V <sub>REF</sub> (V)		
	Min.	Typ.	Max.	Min.	Typ.	Max.
LVC MOS33 <sup>2</sup>	3.135	3.3	3.465	—	—	—
LVC MOS25 <sup>2</sup>	2.375	2.5	2.625	—	—	—
LVC MOS18	1.71	1.8	1.89	—	—	—
LVC MOS15	1.425	1.5	1.575	—	—	—
LVC MOS12 <sup>2</sup>	1.14	1.2	1.26	—	—	—
LV TTL33 <sup>2</sup>	3.135	3.3	3.465	—	—	—
PCI33	3.135	3.3	3.465	—	—	—
SSTL18_I <sup>2</sup> , SSTL18_II <sup>2</sup>	1.71	1.8	1.89	0.833	0.9	0.969
SSTL25_I <sup>2</sup> , SSTL25_II <sup>2</sup>	2.375	2.5	2.625	1.15	1.25	1.35
SSTL33_I <sup>2</sup> , SSTL33_II <sup>2</sup>	3.135	3.3	3.465	1.3	1.5	1.7
HSTL15_I <sup>2</sup>	1.425	1.5	1.575	0.68	0.75	0.9
HSTL18_I <sup>2</sup> , HSTL18_II <sup>2</sup>	1.71	1.8	1.89	0.816	0.9	1.08
LVDS25 <sup>2</sup>	2.375	2.5	2.625	—	—	—
MLVDS25 <sup>1</sup>	2.375	2.5	2.625	—	—	—
LVPECL33 <sup>1, 2</sup>	3.135	3.3	3.465	—	—	—
BLVDS25 <sup>1, 2</sup>	2.375	2.5	2.625	—	—	—
RSDS <sup>1, 2</sup>	2.375	2.5	2.625	—	—	—
SSTL18D_I <sup>2</sup> , SSTL18D_II <sup>2</sup>	1.71	1.8	1.89	—	—	—
SSTL25D_I <sup>2</sup> , SSTL25D_II <sup>2</sup>	2.375	2.5	2.625	—	—	—
SSTL33D_I <sup>2</sup> , SSTL33D_II <sup>2</sup>	3.135	3.3	3.465	—	—	—
HSTL15D_I <sup>2</sup>	1.425	1.5	1.575	—	—	—
HSTL18D_I <sup>2</sup> , HSTL18D_II <sup>2</sup>	1.71	1.8	1.89	—	—	—

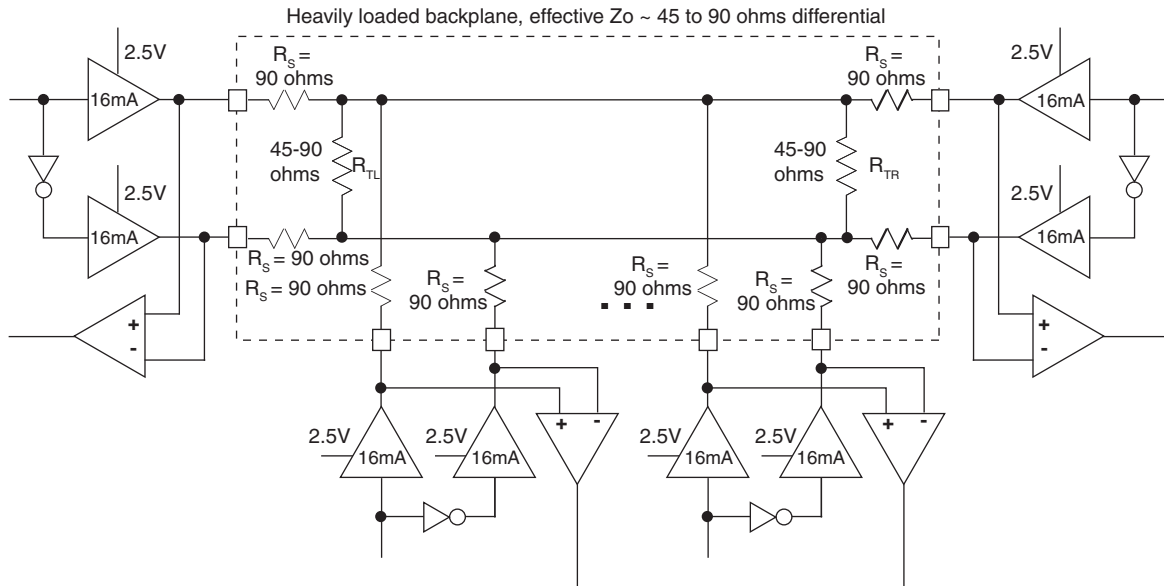
1. Inputs on chip. Outputs are implemented with the addition of external resistors.

2. Input on this standard does not depend on the value of V<sub>CCIO</sub>.

### BLVDS

The LatticeXP2 devices support the BLVDS standard. This standard is emulated using complementary LVCMOS outputs in conjunction with a parallel external resistor across the driver outputs. BLVDS is intended for use when multi-drop and bi-directional multi-point differential signaling is required. The scheme shown in Figure 3-2 is one possible solution for bi-directional multi-point differential signals.

**Figure 3-2. BLVDS Multi-point Output Example**



**Table 3-2. BLVDS DC Conditions<sup>1</sup>**

#### Over Recommended Operating Conditions

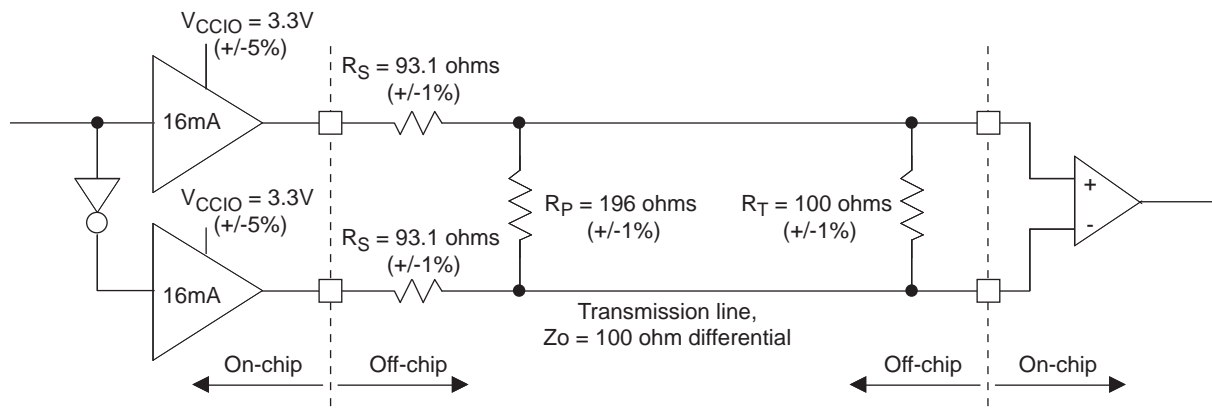
Parameter	Description	Typical		Units
		Zo = 45Ω	Zo = 90Ω	
VCCIO	Output Driver Supply (+/- 5%)	2.50	2.50	V
ZOUT	Driver Impedance	10.00	10.00	Ω
RS	Driver Series Resistor (+/- 1%)	90.00	90.00	Ω
RTL	Driver Parallel Resistor (+/- 1%)	45.00	90.00	Ω
RTR	Receiver Termination (+/- 1%)	45.00	90.00	Ω
VOH	Output High Voltage (After RTL)	1.38	1.48	V
VOL	Output Low Voltage (After RTL)	1.12	1.02	V
VOD	Output Differential Voltage (After RTL)	0.25	0.46	V
VCM	Output Common Mode Voltage	1.25	1.25	V
IDC	DC Output Current	11.24	10.20	mA

1. For input buffer, see LVDS table.

### LVPECL

The LatticeXP2 devices support the differential LVPECL standard. This standard is emulated using complementary LVCMOS outputs in conjunction with a parallel resistor across the driver outputs. The LVPECL input standard is supported by the LVDS differential input buffer. The scheme shown in Figure 3-3 is one possible solution for point-to-point signals.

**Figure 3-3. Differential LVPECL**



**Table 3-3. LVPECL DC Conditions<sup>1</sup>**

#### Over Recommended Operating Conditions

Parameter	Description	Typical	Units
$V_{CCIO}$	Output Driver Supply ( $\pm 5\%$ )	3.30	V
$Z_{OUT}$	Driver Impedance	10	$\Omega$
$R_S$	Driver Series Resistor ( $\pm 1\%$ )	93	$\Omega$
$R_P$	Driver Parallel Resistor ( $\pm 1\%$ )	196	$\Omega$
$R_T$	Receiver Termination ( $\pm 1\%$ )	100	$\Omega$
$V_{OH}$	Output High Voltage (After $R_P$ )	2.05	V
$V_{OL}$	Output Low Voltage (After $R_P$ )	1.25	V
$V_{OD}$	Output Differential Voltage (After $R_P$ )	0.80	V
$V_{CM}$	Output Common Mode Voltage	1.65	V
$Z_{BACK}$	Back Impedance	100.5	$\Omega$
$I_{DC}$	DC Output Current	12.11	mA

1. For input buffer, see LVDS table.

**Register-to-Register Performance (Continued)**

Function	-7 Timing	Units
<b>DSP IP Functions</b>		
16-Tap Fully-Parallel FIR Filter	198	MHz
1024-pt FFT	221	MHz
8X8 Matrix Multiplication	196	MHz

1. These timing numbers were generated using the ispLEVER design tool. Exact performance may vary with device, design and tool version. The tool uses internal parameters that have been characterized but are not tested on every device.

**Derating Timing Tables**

Logic timing provided in the following sections of this data sheet and the Diamond design tools are worst case numbers in the operating range. Actual delays at nominal temperature and voltage for best case process, can be much better than the values given in the tables. The Diamond design tool can provide logic timing numbers at a particular temperature and voltage.

## LatticeXP2 External Switching Characteristics (Continued)

Over Recommended Operating Conditions

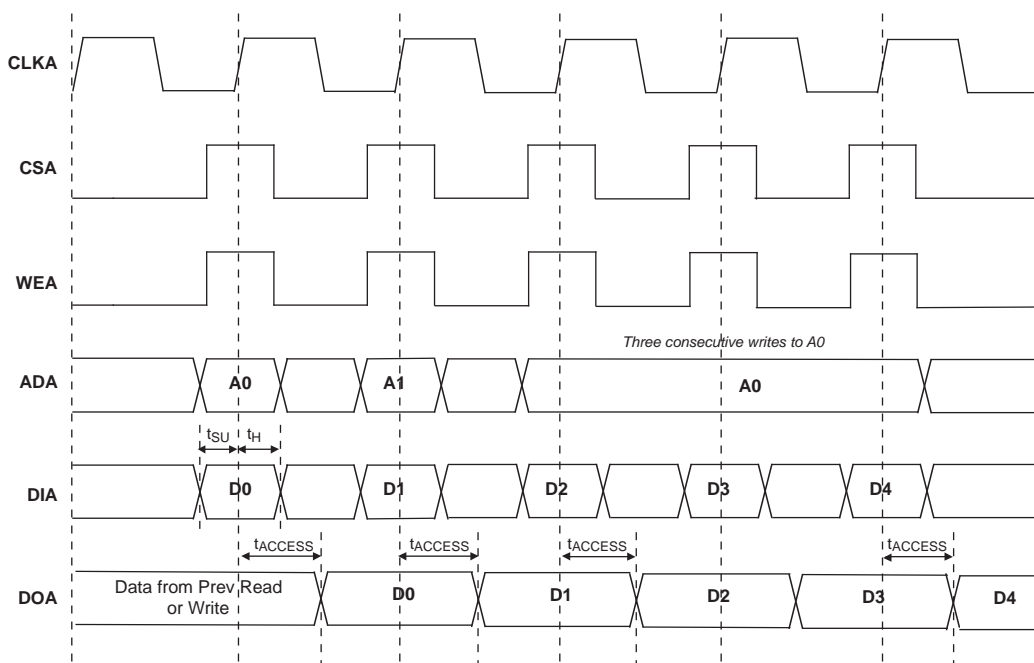
Parameter	Description	Device	-7		-6		-5		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>H_DELLP</sub>	Clock to Data Hold - PIO Input Register with Input Data Delay	XP2-5	0.00	—	0.00	—	0.00	—	ns
		XP2-8	0.00	—	0.00	—	0.00	—	ns
		XP2-17	0.00	—	0.00	—	0.00	—	ns
		XP2-30	0.00	—	0.00	—	0.00	—	ns
		XP2-40	0.00	—	0.00	—	0.00	—	ns
DDR <sup>2</sup> and DDR2 <sup>3</sup> I/O Pin Parameters									
t <sub>DVADQ</sub>	Data Valid After DQS (DDR Read)	XP2	—	0.29	—	0.29	—	0.29	UI
t <sub>DVEDQ</sub>	Data Hold After DQS (DDR Read)	XP2	0.71	—	0.71	—	0.71	—	UI
t <sub>DQVBS</sub>	Data Valid Before DQS	XP2	0.25	—	0.25	—	0.25	—	UI
t <sub>DQVAS</sub>	Data Valid After DQS	XP2	0.25	—	0.25	—	0.25	—	UI
f <sub>MAX_DDR</sub>	DDR Clock Frequency	XP2	95	200	95	166	95	133	MHz
f <sub>MAX_DDR2</sub>	DDR Clock Frequency	XP2	133	200	133	200	133	166	MHz
Primary Clock									
f <sub>MAX_PRI</sub>	Frequency for Primary Clock Tree	XP2	—	420	—	357	—	311	MHz
t <sub>W_PRI</sub>	Clock Pulse Width for Primary Clock	XP2	1	—	1	—	1	—	ns
t <sub>SKW_PRI</sub>	Primary Clock Skew Within a Bank	XP2	—	160	—	160	—	160	ps
Edge Clock (ECLK1 and ECLK2)									
f <sub>MAX_ECLK</sub>	Frequency for Edge Clock	XP2	—	420	—	357	—	311	MHz
t <sub>W_ECLK</sub>	Clock Pulse Width for Edge Clock	XP2	1	—	1	—	1	—	ns
t <sub>SKW_ECLK</sub>	Edge Clock Skew Within an Edge of the Device	XP2	—	130	—	130	—	130	ps

1. General timing numbers based on LVCMOS 2.5, 12mA, 0pf load.

2. DDR timing numbers based on SSTL25.

3. DDR2 timing numbers based on SSTL18.

**Figure 3-8. Write Through (SP Read/Write on Port A, Input Registers Only)**



Note: Input data and address are registered at the positive edge of the clock and output data appears after the positive edge of the clock.

**LatticeXP2 Family Timing Adders<sup>1, 2, 3, 4</sup> (Continued)**
**Over Recommended Operating Conditions**

Buffer Type	Description	-7	-6	-5	Units
HSTL15_I	HSTL_15 class I 4mA drive	0.32	0.69	1.06	ns
HSTL15D_I	Differential HSTL 15 class I 4mA drive	0.32	0.69	1.06	ns
SSTL33_I	SSTL_3 class I	-0.25	0.05	0.35	ns
SSTL33_II	SSTL_3 class II	-0.31	-0.02	0.27	ns
SSTL33D_I	Differential SSTL_3 class I	-0.25	0.05	0.35	ns
SSTL33D_II	Differential SSTL_3 class II	-0.31	-0.02	0.27	ns
SSTL25_I	SSTL_2 class I 8mA drive	-0.25	0.02	0.30	ns
SSTL25_II	SSTL_2 class II 16mA drive	-0.28	0.00	0.28	ns
SSTL25D_I	Differential SSTL_2 class I 8mA drive	-0.25	0.02	0.30	ns
SSTL25D_II	Differential SSTL_2 class II 16mA drive	-0.28	0.00	0.28	ns
SSTL18_I	SSTL_1.8 class I	-0.17	0.13	0.43	ns
SSTL18_II	SSTL_1.8 class II 8mA drive	-0.18	0.12	0.42	ns
SSTL18D_I	Differential SSTL_1.8 class I	-0.17	0.13	0.43	ns
SSTL18D_II	Differential SSTL_1.8 class II 8mA drive	-0.18	0.12	0.42	ns
LVTTTL33_4mA	LVTTTL 4mA drive	-0.37	-0.05	0.26	ns
LVTTTL33_8mA	LVTTTL 8mA drive	-0.45	-0.18	0.10	ns
LVTTTL33_12mA	LVTTTL 12mA drive	-0.52	-0.24	0.04	ns
LVTTTL33_16mA	LVTTTL 16mA drive	-0.43	-0.14	0.14	ns
LVTTTL33_20mA	LVTTTL 20mA drive	-0.46	-0.18	0.09	ns
LVCMOS33_4mA	LVCMOS 3.3 4mA drive, fast slew rate	-0.37	-0.05	0.26	ns
LVCMOS33_8mA	LVCMOS 3.3 8mA drive, fast slew rate	-0.45	-0.18	0.10	ns
LVCMOS33_12mA	LVCMOS 3.3 12mA drive, fast slew rate	-0.52	-0.24	0.04	ns
LVCMOS33_16mA	LVCMOS 3.3 16mA drive, fast slew rate	-0.43	-0.14	0.14	ns
LVCMOS33_20mA	LVCMOS 3.3 20mA drive, fast slew rate	-0.46	-0.18	0.09	ns
LVCMOS25_4mA	LVCMOS 2.5 4mA drive, fast slew rate	-0.42	-0.15	0.13	ns
LVCMOS25_8mA	LVCMOS 2.5 8mA drive, fast slew rate	-0.48	-0.21	0.05	ns
LVCMOS25_12mA	LVCMOS 2.5 12mA drive, fast slew rate	0.00	0.00	0.00	ns
LVCMOS25_16mA	LVCMOS 2.5 16mA drive, fast slew rate	-0.45	-0.18	0.08	ns
LVCMOS25_20mA	LVCMOS 2.5 20mA drive, fast slew rate	-0.49	-0.22	0.04	ns
LVCMOS18_4mA	LVCMOS 1.8 4mA drive, fast slew rate	-0.46	-0.18	0.10	ns
LVCMOS18_8mA	LVCMOS 1.8 8mA drive, fast slew rate	-0.52	-0.25	0.02	ns
LVCMOS18_12mA	LVCMOS 1.8 12mA drive, fast slew rate	-0.56	-0.30	-0.03	ns
LVCMOS18_16mA	LVCMOS 1.8 16mA drive, fast slew rate	-0.50	-0.24	0.03	ns
LVCMOS15_4mA	LVCMOS 1.5 4mA drive, fast slew rate	-0.45	-0.17	0.11	ns
LVCMOS15_8mA	LVCMOS 1.5 8mA drive, fast slew rate	-0.53	-0.26	0.00	ns
LVCMOS12_2mA	LVCMOS 1.2 2mA drive, fast slew rate	-0.46	-0.19	0.08	ns
LVCMOS12_6mA	LVCMOS 1.2 6mA drive, fast slew rate	-0.55	-0.29	-0.02	ns
LVCMOS33_4mA	LVCMOS 3.3 4mA drive, slow slew rate	0.98	1.41	1.84	ns
LVCMOS33_8mA	LVCMOS 3.3 8mA drive, slow slew rate	0.74	1.16	1.58	ns
LVCMOS33_12mA	LVCMOS 3.3 12mA drive, slow slew rate	0.56	0.97	1.38	ns
LVCMOS33_16mA	LVCMOS 3.3 16mA drive, slow slew rate	0.77	1.19	1.61	ns
LVCMOS33_20mA	LVCMOS 3.3 20mA drive, slow slew rate	0.57	0.98	1.40	ns



## sysCLOCK PLL Timing

### Over Recommended Operating Conditions

Parameter	Description	Conditions	Min.	Typ.	Max.	Units
$f_{IN}$	Input Clock Frequency (CLKI, CLKFB)		10	—	435	MHz
$f_{OUT}$	Output Clock Frequency (CLKOP, CLKOS)		10	—	435	MHz
$f_{OUT2}$	K-Divider Output Frequency	CLKOK	0.078	—	217.5	MHz
		CLKOK2	3.3	—	145	MHz
$f_{VCO}$	PLL VCO Frequency		435	—	870	MHz
$f_{PFD}$	Phase Detector Input Frequency		10	—	435	MHz
<b>AC Characteristics</b>						
$t_{DT}$	Output Clock Duty Cycle	Default duty cycle selected <sup>3</sup>	45	50	55	%
$t_{CPA}$	Coarse Phase Adjust		-5	0	5	%
$t_{PH}$ <sup>4</sup>	Output Phase Accuracy		-5	0	5	%
$t_{OPJIT}$ <sup>1</sup>	Output Clock Period Jitter	$f_{OUT} > 400$ MHz	—	—	±50	ps
		$100 \text{ MHz} < f_{OUT} < 400$ MHz	—	—	±125	ps
		$f_{OUT} < 100$ MHz	—	—	0.025	UIPP
$t_{SK}$	Input Clock to Output Clock Skew	N/M = integer	—	—	±240	ps
$t_{OPW}$	Output Clock Pulse Width	At 90% or 10%	1	—	—	ns
$t_{LOCK}$ <sup>2</sup>	PLL Lock-in Time	25 to 435 MHz	—	—	50	μs
		10 to 25 MHz	—	—	100	μs
$t_{IPJIT}$	Input Clock Period Jitter		—	—	±200	ps
$t_{FBKDL}$	External Feedback Delay		—	—	10	ns
$t_{HI}$	Input Clock High Time	90% to 90%	0.5	—	—	ns
$t_{LO}$	Input Clock Low Time	10% to 10%	0.5	—	—	ns
$t_{RSTKW}$	Reset Signal Pulse Width (RSTK)		10	—	—	ns
$t_{RSTW}$	Reset Signal Pulse Width (RST)		500	—	—	ns

1. Jitter sample is taken over 10,000 samples of the primary PLL output with clean reference clock.

2. Output clock is valid after  $t_{LOCK}$  for PLL reset and dynamic delay adjustment.

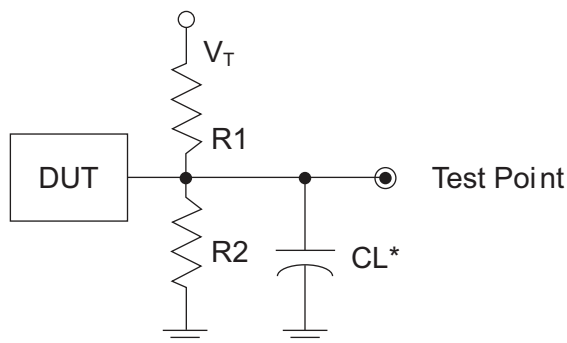
3. Using LVDS output buffers.

4. Relative to CLKOP.

### Switching Test Conditions

Figure 3-11 shows the output test load that is used for AC testing. The specific values for resistance, capacitance, voltage, and other test conditions are shown in Table 3-6.

**Figure 3-11. Output Test Load, LVTTTL and LVCMOS Standards**



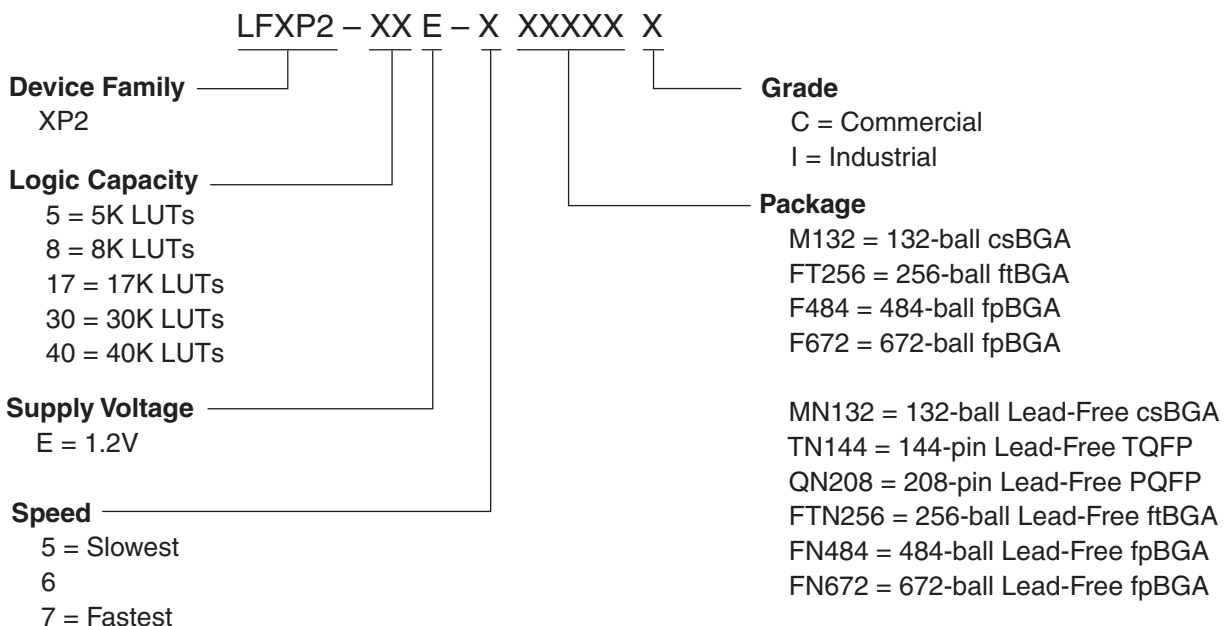
\*CL Includes Test Fixture and Probe Capacitance

**Table 3-6. Test Fixture Required Components, Non-Terminated Interfaces**

Test Condition	R <sub>1</sub>	R <sub>2</sub>	C <sub>L</sub>	Timing Ref.	V <sub>T</sub>
LVTTTL and other LVCMOS settings (L -> H, H -> L)	$\infty$	$\infty$	0pF	LVCMOS 3.3 = 1.5V	—
				LVCMOS 2.5 = V <sub>CCIO</sub> /2	—
				LVCMOS 1.8 = V <sub>CCIO</sub> /2	—
				LVCMOS 1.5 = V <sub>CCIO</sub> /2	—
				LVCMOS 1.2 = V <sub>CCIO</sub> /2	—
LVCMOS 2.5 I/O (Z -> H)	$\infty$	1M $\Omega$		V <sub>CCIO</sub> /2	—
LVCMOS 2.5 I/O (Z -> L)	1M $\Omega$	$\infty$		V <sub>CCIO</sub> /2	V <sub>CCIO</sub>
LVCMOS 2.5 I/O (H -> Z)	$\infty$	100		V <sub>OH</sub> - 0.10	—
LVCMOS 2.5 I/O (L -> Z)	100	$\infty$		V <sub>OL</sub> + 0.10	V <sub>CCIO</sub>

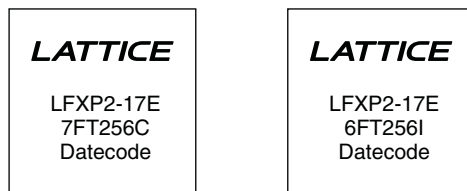
Note: Output test conditions for all other interfaces are determined by the respective standards.

### Part Number Description



### Ordering Information

The LatticeXP2 devices are marked with a single temperature grade, either Commercial or Industrial, as shown below.



## For Further Information

A variety of technical notes for the LatticeXP2 FPGA family are available on the Lattice Semiconductor web site at [www.latticesemi.com](http://www.latticesemi.com).

- TN1136, [LatticeXP2 sysIO Usage Guide](#)
- TN1137, [LatticeXP2 Memory Usage Guide](#)
- TN1138, [LatticeXP2 High Speed I/O Interface](#)
- TN1126, [LatticeXP2 sysCLOCK PLL Design and Usage Guide](#)
- TN1139, [Power Estimation and Management for LatticeXP2 Devices](#)
- TN1140, [LatticeXP2 sysDSP Usage Guide](#)
- TN1141, [LatticeXP2 sysCONFIG Usage Guide](#)
- TN1142, [LatticeXP2 Configuration Encryption and Security Usage Guide](#)
- TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#)
- TN1220, [LatticeXP2 Dual Boot Feature](#)
- TN1130, [LatticeXP2 Soft Error Detection \(SED\) Usage Guide](#)
- TN1143, [LatticeXP2 Hardware Checklist](#)

For further information on interface standards refer to the following websites:

- JEDEC Standards (LVTTTL, LVCMOS, SSTL, HSTL): [www.jedec.org](http://www.jedec.org)
- PCI: [www.pcisig.com](http://www.pcisig.com)

### Revision History

Date	Version	Section	Change Summary
May 2007	01.1	—	Initial release.
September 2007	01.2	DC and Switching Characteristics	Added JTAG Port Timing Waveforms diagram.
			Updated sysCLOCK PLL Timing table.
		Pinout Information	Added Thermal Management text section.
February 2008	01.3	Architecture	Added LVC MOS33D to Supported Output Standards table.
			Clarified: "This Flash can be programmed through either the JTAG or Slave SPI ports of the device. The SRAM configuration space can also be infinitely reconfigured through the JTAG and Master SPI ports."
			Added External Slave SPI Port to Serial TAG Memory section. Updated Serial TAG Memory diagram.
		DC and Switching Characteristics	Updated Flash Programming Specifications table.
			Added "8W" specification to Hot Socketing Specifications table.
			Updated Timing Tables
			Clarifications for IIH in DC Electrical Characteristics table.
			Added LVC MOS33D section
			Updated DOA and DOA (Regs) to EBR Timing diagrams.
			Removed Master Clock Frequency and Duty Cycle sections from the LatticeXP2 sysCONFIG Port Timing Specifications table. These are listed on the On-chip Oscillator and Configuration Master Clock Characteristics table.
			Changed CSSPIN to CSSPISN in description of $t_{SCS}$ , $t_{SCSS}$ , and $t_{SCSH}$ parameters. Removed $t_{SOE}$ parameter.
			Clarified On-chip Oscillator documentation
			Added Switching Test Conditions
		Pinout Information	Added "True LVDS Pairs Bonding Out per Bank," "DDR Banks Bonding Out per I/O Bank," and "PCI capable I/Os Bonding Out per Bank" to Pin Information Summary in place of previous blank table "PCI and DDR Capabilities of the Device-Package Combinations"
			Removed pinout listing. This information is available on the LatticeXP2 product web pages
		Ordering Information	Added XP2-17 "8W" and all other family OPNs.
April 2008	01.4	DC and Switching Characteristics	Updated Absolute Maximum Ratings footnotes.
			Updated Recommended Operating Conditions Table footnotes.
			Updated Supply Current (Standby) Table
			Updated Initialization Supply Current Table
			Updated Programming and Erase Flash Supply Current Table
			Updated Register to Register Performance Table
			Updated LatticeXP2 External Switching Characteristics Table
			Updated LatticeXP2 Internal Switching Characteristics Table
			Updated sysCLOCK PLL Timing Table